

Search Notes

Application/Control No.

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Examiner

Jared I. Rutz

Applicant(s)/Patent under
Reexamination

LIN ET AL.

Art Unit

2187

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Inventor search PALM	8/15/2005	JIR
Inventor search EAST	8/15/2005	JIR
711/6,54,40,44,45,158 - text search, see search history	8/11/2005	JIR
710/6,54,40,44,45 - text search see search history	8/12/2005	JIR
Searched ACM	8/12/2005	JIR
Searched IEEE	8/12/2005	jir